

## **Precise Electrostatic Spectrometers for Time-of-Flight Mass Measurements**

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Different type of Time-of-Flight Spectrometers (TOF) for mass measurement will be presented. Developed and built at University in Giessen in cooperation with GSI, these devices are used for analyzing different kind of ion-mass-spectra at low energy beam facilities like SHIP at GSI or MLL at Munich.

A new type of Mutiple-Reflection-TOF (Multi-TOF) with a mass-resolution over 300,000 allows in addition to mass analysis separate ions of interest for further experiments.

To fulfill all ion-optical conditions in this highly complicated system, mostly all electronic controllers and drivers were constructed by the Muti-TOF team itself. An overview will be given.

What: Cyclotron Colloquium, TAMU

When: Friday July 30, 2010 at 3:45pm

Where: Conference Room